


<b>Search Notes</b>  	<b>Application/Control No.</b>  10810823	<b>Applicant(s)/Patent Under Reexamination</b>  CHO ET AL.
	<b>Examiner</b>  HELEN SHIBRU	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
modified search	06/30/2008	hs
updated search	02/09/2009	hs
MODIFIED SEARCH	07/14/09	HS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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